

Cavity Optimization for Compact Accelerator- based Free-electron Maser

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TPU

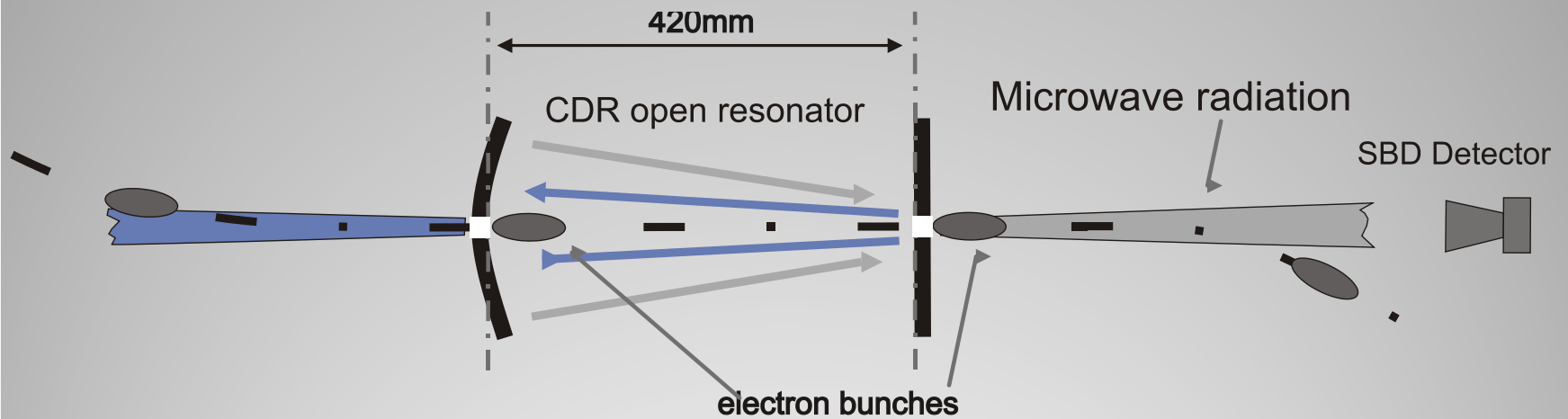
In collaboration with

A. Aryshev, S. Araki, M. Fukuda, N. Terunuma, J. Urakawa
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P. Karataev
John Adams Institute at Royal Holloway, University of London

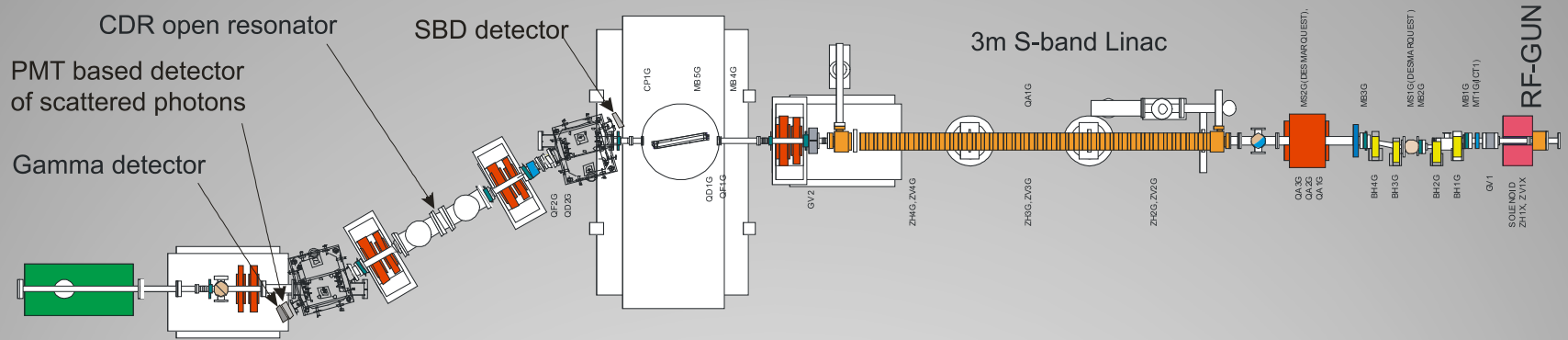
G. Naumenko, A. Potylitsyn, L. Sukhikh
Tomsk Polytechnic University

K. Sakaue
Waseda University



A.P. Potylitsyn, Phys. Rev. E 60 (1999) 2272.

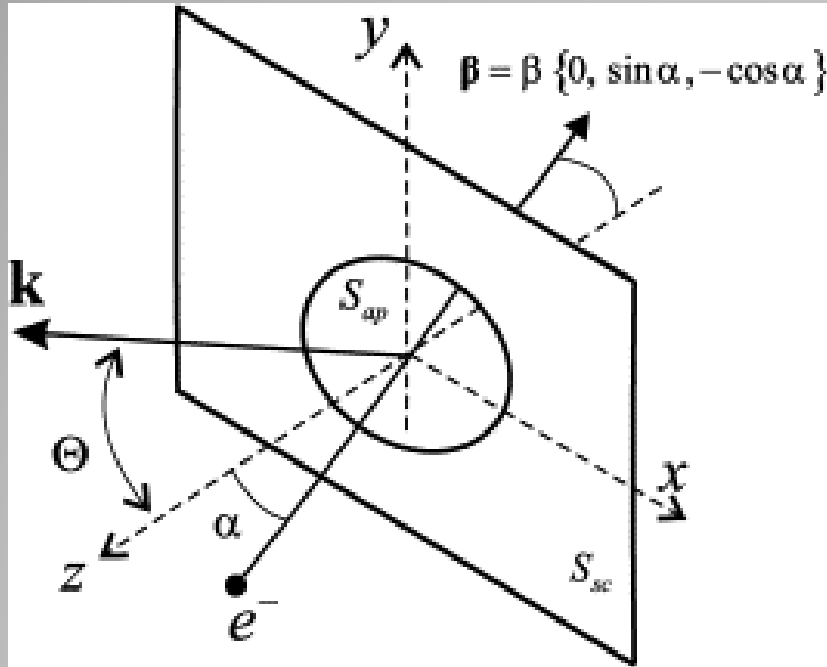
Compact Accelerator-based Free-Electron Maser



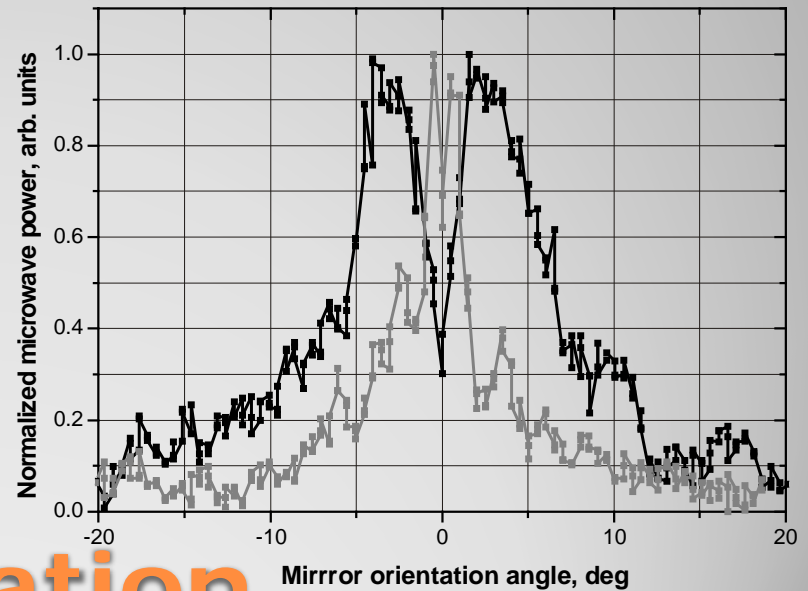
Energy	30 MeV ($\gamma = 62$)
Intensity	1 nC/bunch
Num. of Bunches	100
Bunch spacing	2.8 ns
Bunch length	<10 ps
Repetition rate, nominal	3.13 Hz
Emittance (round)	$5 \pi \text{ mm} \cdot \text{mrad}$
$\sigma_x \sigma_y$ in SCDR chamber	200 μm , 200 μm

LUCX, compact linear accelerator

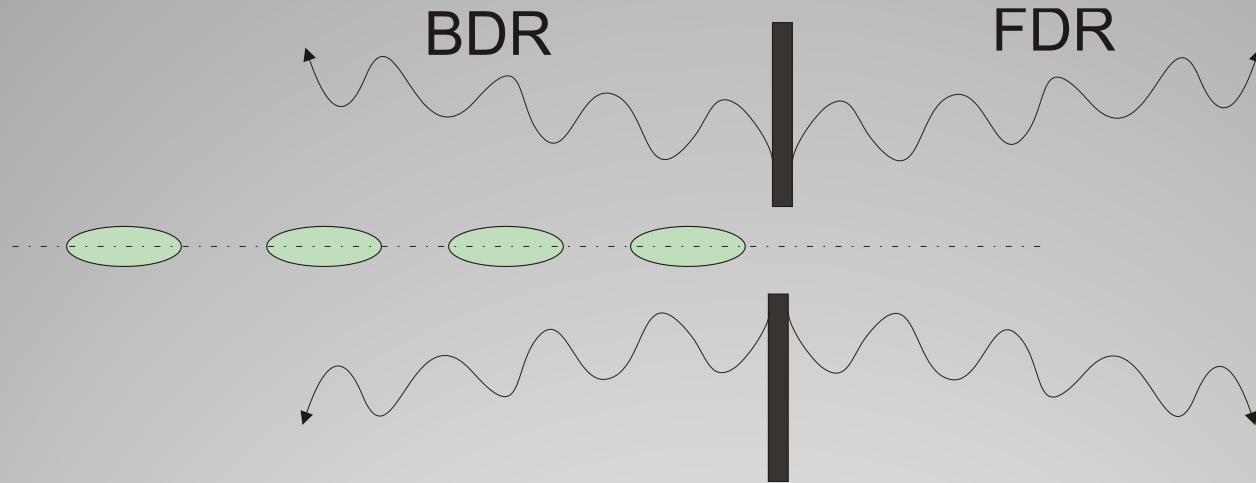
S. Liu, M. Fukuda, S. Araki, N. Terunuma, J. Urakawa, K. Hirano, N. Sasao, Nuclear Instruments and Methods A 584 (2008) 1-8.



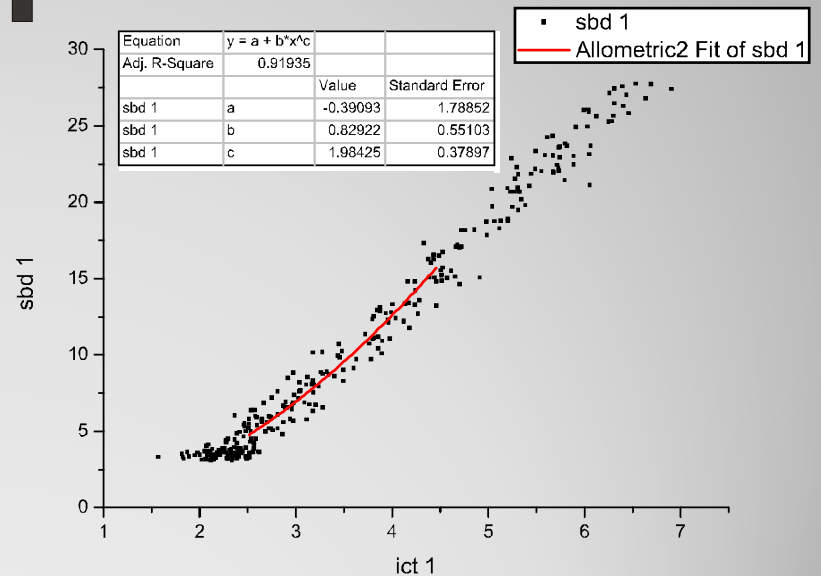
- Diffraction radiation (DR) appears when a charged particle moves in the vicinity of a medium
- $I_{DR} \sim N_e$



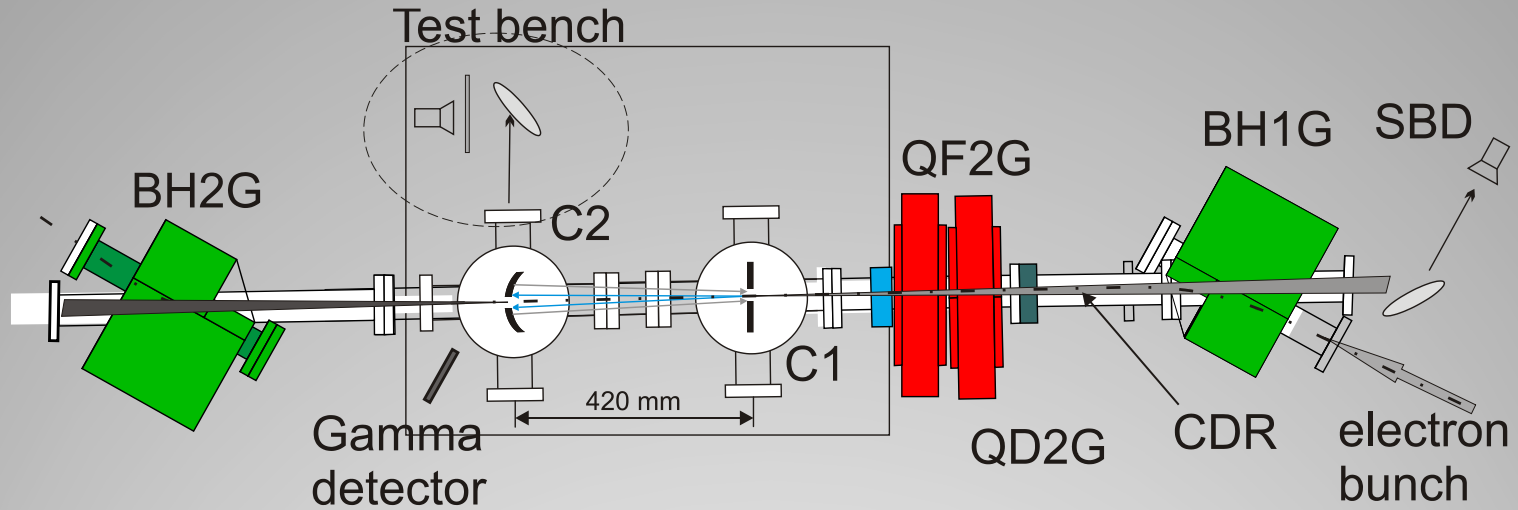
Diffraction Radiation



- CDR is generated by sequence of charged bunches
- $I_{\text{CDR}} \sim N_e^2$

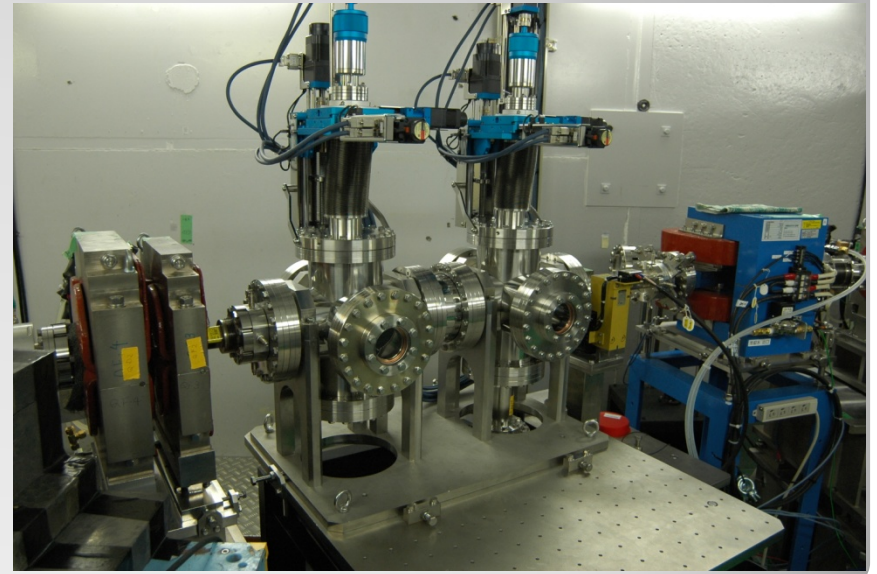


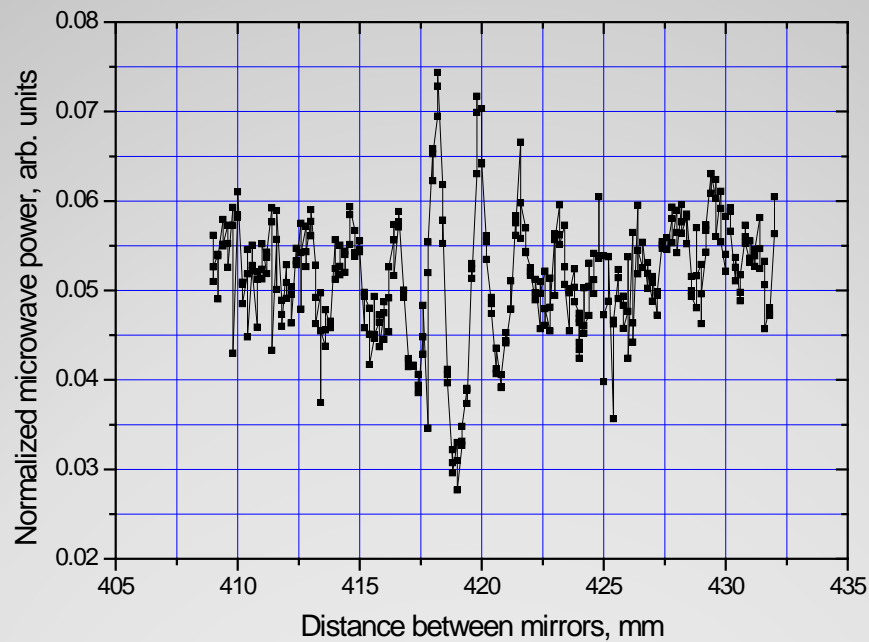
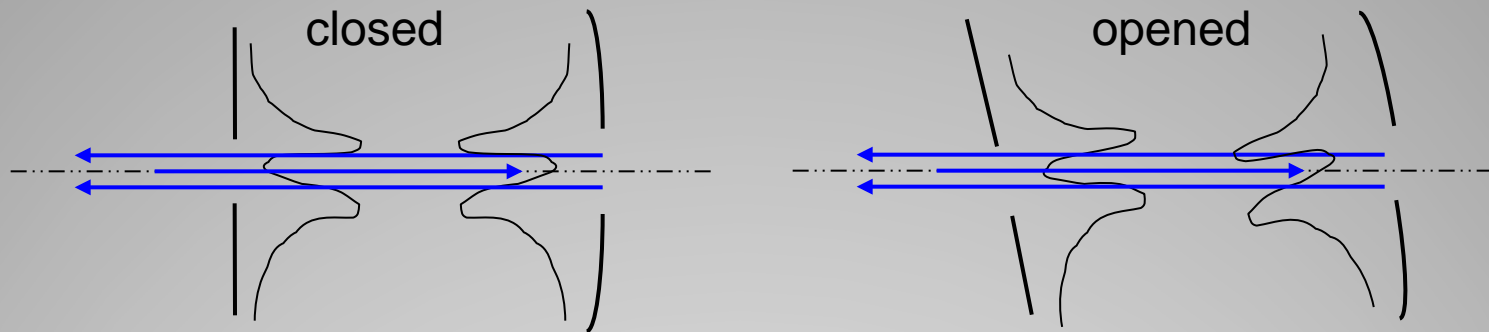
Coherent Diffraction Radiation



- 2 6-way crosses
- 2 4D vacuum manipulation systems
- 2 aluminum mirrors

CDR on LUCX





CDR on LUCX: Cavity length scan

$$T_0 = \frac{AT^2}{(1 + A^2R^2 - 2AR \cos \delta)}$$

$$R_s = \frac{\left(\cos \theta_i - n \sqrt{1 - \left(\frac{1}{n} \sin \theta_i \right)^2} \right)^2}{\left(\cos \theta_i + n \sqrt{1 - \left(\frac{1}{n} \sin \theta_i \right)^2} \right)^2}$$

$$T_s = 1 - R_s$$

$$\varepsilon = \varepsilon' + i\varepsilon''$$

$$n^2 + k^2 = \text{Re}(\varepsilon) \quad 2nk = \text{Im}(\varepsilon)$$

Al

$$\varepsilon' = 1 - \frac{\omega_p^2}{\Gamma^2 + \omega^2}$$

$$\varepsilon'' = \frac{\omega_p^2 \Gamma}{\omega(\Gamma^2 + \omega^2)}$$

Si

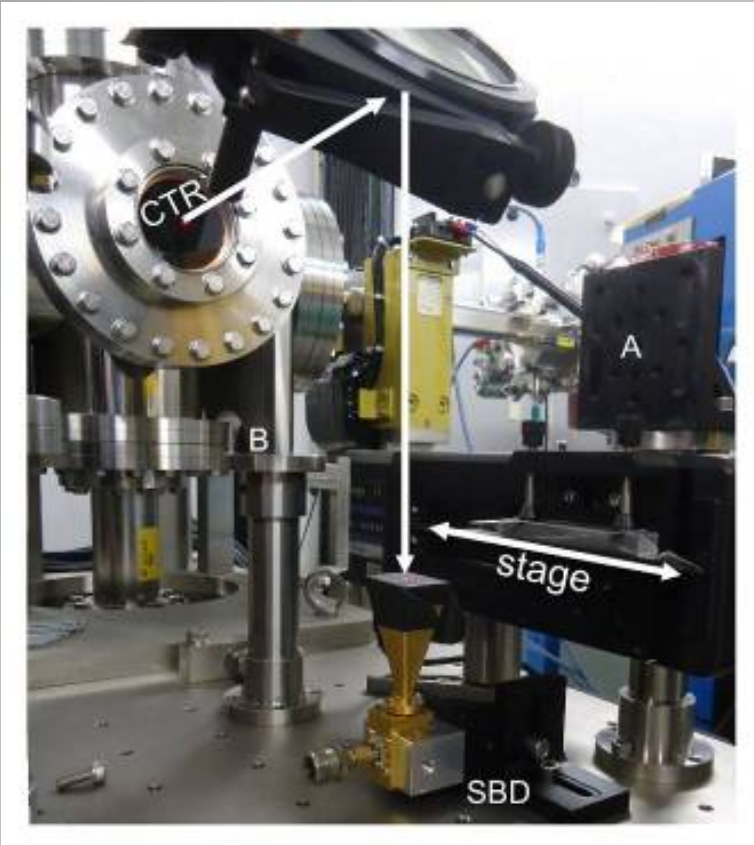
$$\varepsilon' = \varepsilon_\infty \left[1 - \frac{\omega_p^2 \tau^2}{1 + \omega^2 \tau^2} \right]$$

$$\varepsilon'' = \frac{\varepsilon_\infty \omega_p^2 \tau}{\omega(1 + \omega^2 \tau^2)} \quad \omega_p = \frac{N_e e^2}{\varepsilon_0 \varepsilon_\infty m^*}$$

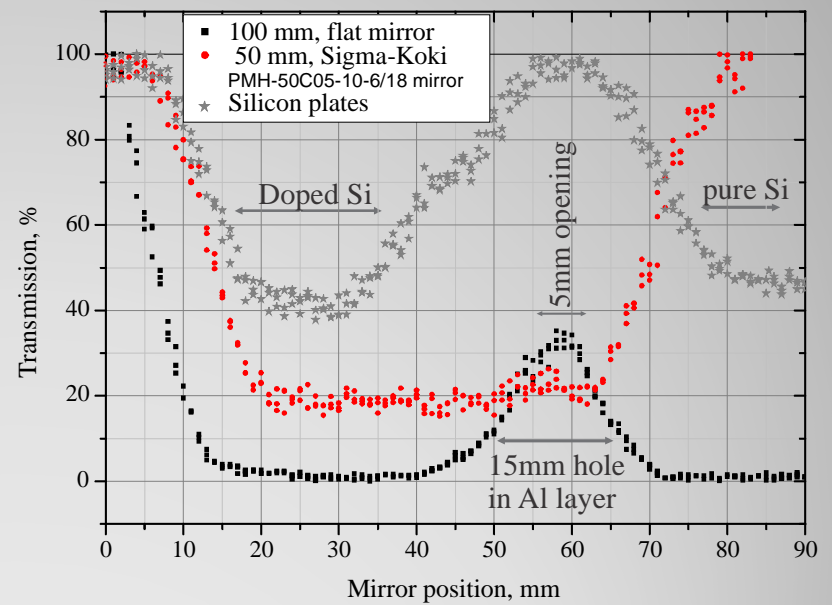
M.I. Markovic, A.D. Rakic. Determination of optical properties of aluminium including electron reradiation in the Lorentz-Drude model. Opt.and Laser Tech., v. 22, No. 6, 394-398, 1990.

R.T. Kinasewitz, B.Senitzky. Investigation of complex permittivity of n-type silicon at millimeter wavelengths. J. Appl. Phys., v. 54, No. 6, 3394-3398, 1983.

Transmission calculation



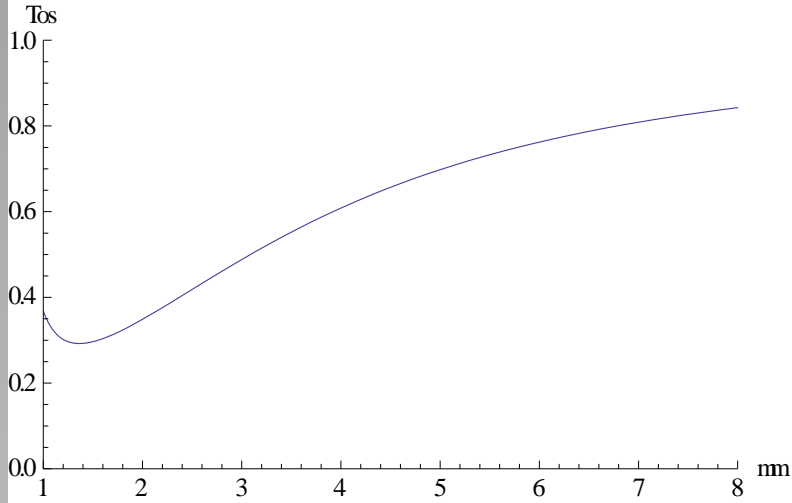
Material	Transmission coefficient	
	<i>Experiment</i>	<i>Theory</i>
Aluminized mirror	0	0
Doped silicon	0.42	0.42
Normal silicon	0.45	0.42



Mirror test bench

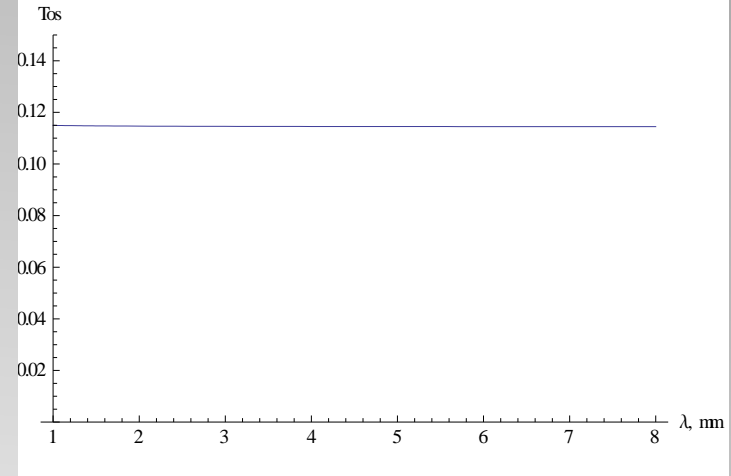
Si

h=100 mkm



Al

h=2 nm

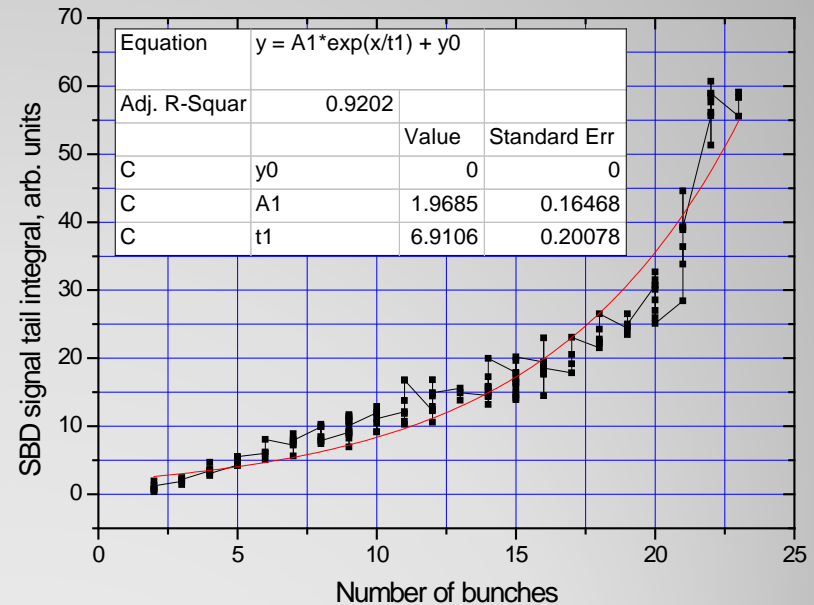
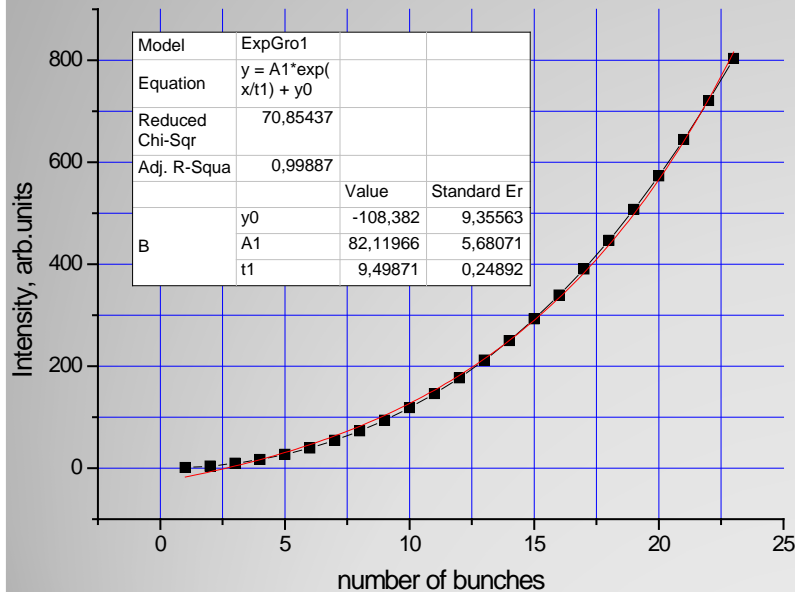


<i>Aluminum, nm</i>	<i>Silicon, mkm</i>	<i>Transmission coefficient, %</i>
2	100	6.5
	150	5.3
	300	4.0
3	100	3.4
	150	2.7
	300	2.1
4	50	2.7
	100	2.0
	150	1.6

Mirror diameter = 100 mm
 Thickness of Si substrate should be
 more than 100 mkm for durability

New mirror design

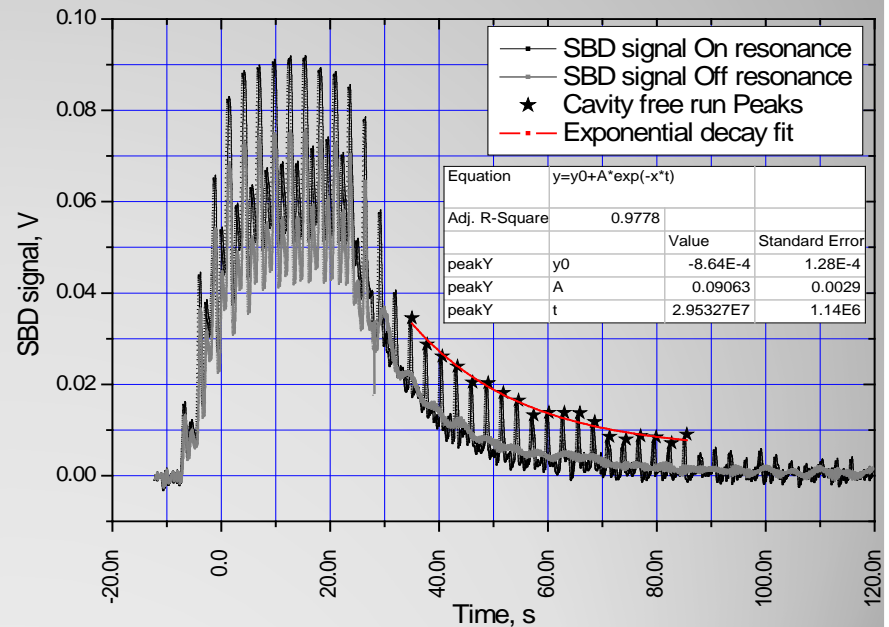
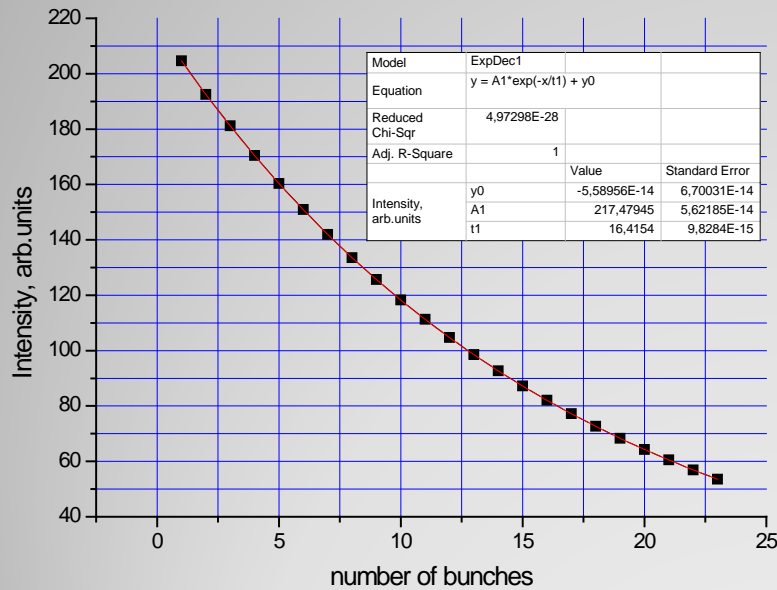
- $E_{SCDR} = a E_{Cav}$ – addition to electric field by stimulation (depends on electric field stored in cavity)
- E_{DR} – electric field generated by single bunch
- d – loss in resonator
- $E_{tot,2} = d E_{DR} + E_{DR} + ad E_{DR} = E_{DR} (1 + d (1+a)) = E_{DR} (1+b)$ – electric field in resonator after second bunch
- $E_{tot,i} = E_{DR} (1-b^i)/(1-b)$ – electric field in resonator after i-th bunch



Stimulation

Chitrlada Settakorn, Michael Hernandez, and Helmut Wiedemann
Stanford Linear Accelerator Center, Stanford University, Stanford, CA
94309, SLAC-PUB-7587 August 1997

- $E_{tot,i} = E_{DR} (1-b^N)/(1-b) d^{i-N}$ – where N is number of bunches in train ($i > N$)



Cavity decay

Thank you for attention